

**Search Notes**

Application/Control No.

10/627,536

Examiner

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Applicant(s)/Patent under  
Reexamination

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Art Unit

2825

**SEARCHED**

Class	Subclass	Date	Examiner
327	52-58	2/16/2005	PD
327	65	2/16/2005	PD
327	108	2/16/2005	PD
327	112	2/16/2005	PD
327	560	2/16/2005	PD
327	563	2/16/2005	PD

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
Search	above	2/18/2005	PD

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST, IEEE	2/16/2005	PD